



## CHIANG IS OSA FELLOW

The Optical Society of America has awarded the rank of Fellow to 56 of its members, bringing the total number to 756. According to the Society's bylaws, "Any regular member who has served with distinction in the advancement of optics is eligible for transfer to the class of Fellow." No more than one-tenth of the total membership may be Fellows. The 1988 Fellows were approved by the Board of Directors based on the recommendation of the 1987 Fellows and Honorary Members Committee. Professor Fu-pen Chiang, State University of New York at Stony Brook was one of the members so honored. Dr. Chiang, an SEM Member, was recognized for the development of optical methods of experimental mechanics and metrology such as moiré, photo-elasticity, and random speckle techniques.

## MODAL ANALYSIS

The editors of EXPERIMENTAL TECHNIQUES (E/T) invite authors to submit short application/technique articles on modal analysis for possible publication in E/T. The focus of SEM's INTERNATIONAL JOURNAL OF ANALYTICAL AND EXPERIMENTAL MODAL ANALYSIS is on analytical and experimental papers. E/T is the place for the researcher/author to share laboratory application techniques and problem-solving. See the "Invitation to Publish" page in this issue for submission guidelines.



## GALLAGHER NAMED FELLOW OF ASTM

Joseph P. Gallagher, supervisor of the Structural Integrity Division Research Institute at the University of Dayton, OH is a 1988 recipient of ASTM's Award of Merit.

Gallagher, an SEM Member, received the award at ceremonies hosted by ASTM Committee E-24 on Mechanical Testing. He was honored for outstanding leadership in promoting the development of ASTM standards, interaction, and cooperation within the technical committee. The Award of Merit, and the accompanying honorary title of Fellow of the Society, were established in 1949 to recognize productive service to ASTM, marked leadership, outstanding contributions or publication of papers.

## 1989 SEM BUYERS' GUIDE

By action of the SEM Executive Board, the SEM Buyers' Guide will be published in EXPERIMENTAL TECHNIQUES in odd-numbered years only. The 1987 Buyers' Guide was published in July; the next Guide will appear in July 1989.

Those suppliers wishing to be listed may contact the SEM Editorial Department to ensure that their names will be included in the questionnaire mailing in January of 1989.

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- 26 Delsen Testing Laboratories, Inc.
- 2 Ealing Electro-Optics, Inc.
- 10 Eaton Corporation APD
- 26 Fatigue Technology, Inc.
- 26 Hitec Corporation
- 7 Hitec Products, Inc.
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- 9 Precision Foil Technology, Inc.
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